

Notice of References Cited	Application/Control No. 10/658,983		Applicant(s)/Patent Under Reexamination SHIDLA ET AL.	
	Examiner Ryan D. Coyer		Art Unit 2191	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,269,827	09-2007	Metzger, Markus T.	717/151
*	B	US-6,640,313	10-2003	Quach, Nhon	714/10
*	C	US-6,625,688	09-2003	Fruehling et al.	711/109
*	D	US-6,134,675	10-2000	Raina, Rajesh	714/37
*	E	US-5,557,761	09-1996	Chan et al.	717/156
*	F	US-7,234,136	06-2007	Tirumalai et al.	717/161
*	G	US-2004/0243882	12-2004	Zhou, Charles J.	714/038
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nickel et al., "REESE: A Method of Soft Error Detection in Microprocessors", IEEE, 2001, 10pgs.
	V	Oh et al., "Error Detection by Duplicated Instructions in Super-Scalar Processors", IEEE, 2002, 13pgs.
	W	Reinhardt et al., "Transient Fault Detection via Simultaneous Multithreading", ACM, 2000, 12pgs.
	X	Shirvani et al., "Software-Implemented Hardware Fault Tolerance Experiments COTS in Space", ONR, 2000, 2pgs.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.